Abstract: In the search for the ideal computer memory, transition metal oxides have emerged as one of several leading candidates for Resistive RAM memory. The memory works using applied fields to move and create oxygen vacancies which store the information. Data on the DC, temporal switching, switching statistics and noise for TaO2 and TiO2 memory devices are presented and analyzed in terms of quantum conductive filaments formed/destroyed by oxygen vacancy dynamics. The expected switching statistics, electrical properties and bit error rates can be modeled by fraction order diffusion and stable distributions relating to the dispersive transport of vacancies.

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